



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: Yamada) Group Art Unit: 2829
Serial No: 09/865,528)
Filed: May 29, 2001)
Title: Semiconductor Device Test Method)
and Semiconductor Device Tester)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

Dear Sir:

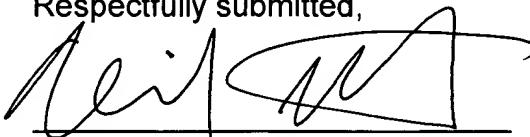
Applicant notes the Examiner's reasons for allowance. No inference or conclusion should be drawn that Applicant believes that the Examiner's reasons for allowance are the only reasons the claims are patentable. Indeed, the Examiner's statements focus on an independent claim and no mention is made with respect to other independent claims as well as the dependent claims, which include other and/or additional inventive aspects. Applicant interprets the Examiner's statement to be not exhaustive. That is, the Examiner's statement is directed solely to certain patentable features in an independent claim and is in no way exhaustive relative to all of the independent claim(s) or the dependent claims.

Moreover, no inference or conclusion should be drawn that the features set forth in the Examiner's statement are any more or less significant than other features of the

claimed invention of this application. It is the combination of features of a given claim that render the (independent or dependent) claim patentable.

Finally, although Applicant agrees with the Examiner's ultimate conclusion that the inventions, as claimed herein, are patentable over the prior art, as described in the above-referenced application, there are many inventions described and illustrated therein. Indeed, other inventions described and illustrated in the application may or may not include one, some or all of the features set forth in the Examiner's statement.

Respectfully submitted,



Neil Steinberg, Reg. No. 34,735
Telephone No. 650-968-8079

Date: June 24, 2004



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Mail Stop Issue Fee
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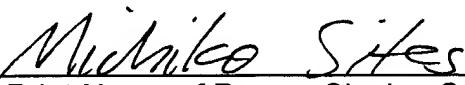
Certificate of Mailing under 37 CFR 1.8

I hereby certify that the attached: **(1) Transmittal of Payment of Issue Fee** (1 page + 1 copy), **(2) Fee Transmittal** (1 page + 1 copy), **(3) Fee (Check)** for \$1,645.00, and **(4) Comments on Statement of Reasons for Allowance** are being deposited with the United States Postal Service with sufficient postage as first class mail in an envelop addressed to:

Mail Stop ISSUE FEE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

on June 24, 2004.


Signature


Print Name of Person Signing Certificate